

**INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION**

A circular stamp from the Oficina Intercalar de Patentes y Marcas (OIPE) in Madrid, Spain. The outer ring contains the acronym "OIPE" at the top and "PATENT & TRADEMARK OFFICE" at the bottom. The center of the stamp contains the date "MAR 01 2004" and the code "JCB4" at the bottom right.

(PTO-1449)

## U.S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 11-199345	07/27/1999	TEIJIN LTD		(Japan w/English Abstract)	
		JP 57-196777	12/02/1982			(Japan w/English Abstract)	
		JP 7-263271	10/13/1995	MARCON ELECTRON CO LTD		(Japan w/English Abstract)	
		JP 11-260661	09/24/1999	MATSUSHITA ELECTRIC IND CO LTD		(Japan w/English Abstract)	
		JP 11-233387	08/27/1999	MATSUSHITA ELECTRIC IND CO LTD		(Japan w/English Abstract)	
		JP 2-58315	02/27/1990	MATSUSHITA ELECTRIC IND CO LTD		(Japan w/English Abstract)	

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER  
Mayes

DATE CONSIDERED  
4/23/04

*[Signature]*  
\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.**